

IXTX200N10L2-VB Datasheet N-Channel 100 V (D-S) MOSFET

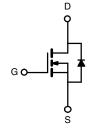
PRODUCT SUMMARY					
V _{DS} (V)	100				
$R_{DS(on)}(\Omega)$ at $V_{GS} = 10 \text{ V}$	0.002				
I _D (A) ^a	320				
Configuration	Single				

FEATURES

- Trench Power MOSFET
- Package with Low Thermal Resistance
- \bullet 100 % R_g and UIS Tested







Top View

N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER	SYMBOL	LIMIT	UNIT			
Drain-Source Voltage	V_{DS}	100	V			
Gate-Source Voltage	V_{GS}	± 20	V			
Continuous Drain Current	T _C = 25 °C ^a	1	320			
	T _C = 125 °C	l _D	240			
Continuous Source Current (Diode Conductio	I _S	320	Α			
Pulsed Drain Current ^b	I _{DM}	1220				
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	123			
Single Pulse Avalanche Energy	L = 0.1 IIII	E _{AS}	366	mJ		
Maximum Power Dissipation ^b	T _C = 25 °C	D	650	W		
	T _C = 125 °C	P_{D}	183	, vv		
Operating Junction and Storage Temperature Range		T_J,T_stg	- 55 to + 175	°C		

THERMAL RESISTANCE RATINGS						
PARAMETER		SYMBOL	LIMIT	UNIT		
Junction-to-Ambient	nbient PCB Mount ^c			°C/W		
Junction-to-Case (Drain)		R_{thJC}	0.6	C/VV		

Notes

- a. Base on Tc = 25°C.
- b. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 %.
- c. When mounted on 1" square PCB (FR-4 material).
- d. Parametric verification ongoing.

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PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							l
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0$, $I_D = 250 \mu A$		100	-	-	V
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		3.0	3.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA
		V _{GS} = 0 V	V _{DS} = 100 V	-	-	1	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 V$	V _{DS} = 100 V, T _J = 125 °C	-	-	50	μΑ
		V _{GS} = 0 V	V _{DS} = 100 V, T _J = 175 °C	-	-	500	
On-State Drain Current ^a	I _{D(on)}	V _{GS} = 10 V	$V_{DS} \ge 5 V$	120	-	-	Α
		V _{GS} = 10 V	I _D = 20 A	-	0.0020	-	Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 10 V	I _D = 30 A, T _J = 125 °C		0.0054	-	
		V _{GS} = 10 V	I _D = 30 A, T _J = 175 °C	-	0.0080	-	
Forward Transconductance ^b	9 _{fs}	V _{DS} = 15 V, I _D = 30 A		-	82	-	S
Dynamic ^b							•
Input Capacitance	C _{iss}			-	9780	12230	
Output Capacitance	C _{oss}	$V_{GS} = 0 V$	$V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	-	3070	3840	pF
Reverse Transfer Capacitance	C _{rss}	1		-	305	385	
Total Gate Charge ^c	Qg			-	125	190	
Gate-Source Charge ^c	Q _{gs}	V _{GS} = 10 V	$V_{DS} = 50 \text{ V}, I_{D} = 70 \text{ A}$	-	28	-	nC
Gate-Drain Charge ^c	Q _{gd}	1		-	46	-	
Gate Resistance	R _g	f = 1 MHz		1.6	3.3	5	Ω
Turn-On Delay Time ^c	t _{d(on)}				16	25	
Rise Time ^c	t _r	$V_{DD} = 50 \text{ V}, \text{ R}_{L} = 0.7 \Omega$ $I_{D} \cong 70 \text{ A}, V_{GEN} = 10 \text{ V}, \text{ R}_{g} = 1 \Omega$		-	110	165	- ns
Turn-Off Delay Time ^c	t _{d(off)}			-	40	60	
Fall Time ^c	t _f			-	12	20	
Source-Drain Diode Ratings and Chara	acteristics ^b	•					
Pulsed Current ^a	I _{SM}			-	-	480	Α
Forward Voltage	V _{SD}	I _F = 100 A, V _{GS} = 0		-	0.9	1.5	V

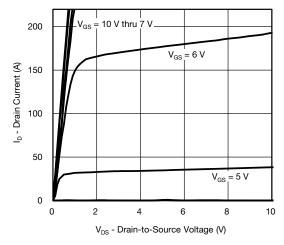
Notes

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.

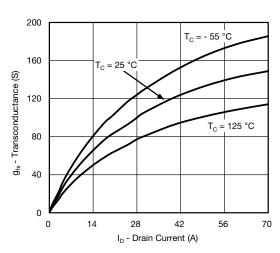
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



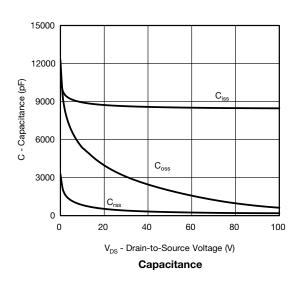
TYPICAL CHARACTERISTICS (T_A = 25 °C, unless otherwise noted)

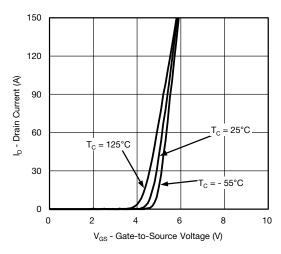


Output Characteristics

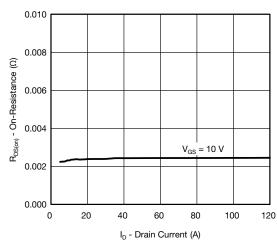


Transconductance

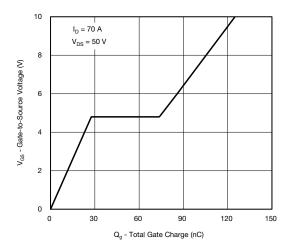




Transfer Characteristics



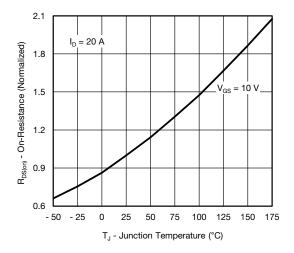
On-Resistance vs. Drain Current



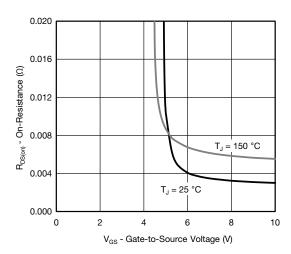
Gate Charge



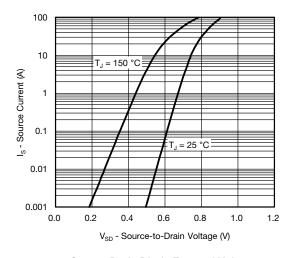
TYPICAL CHARACTERISTICS ($T_A = 25 \, ^{\circ}\text{C}$, unless otherwise noted)



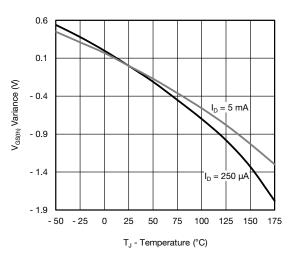
On-Resistance vs. Junction Temperature



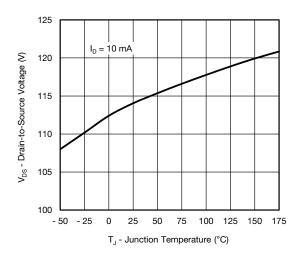
On-Resistance vs. Gate-to-Source Voltage



Source Drain Diode Forward Voltage



Threshold Voltage

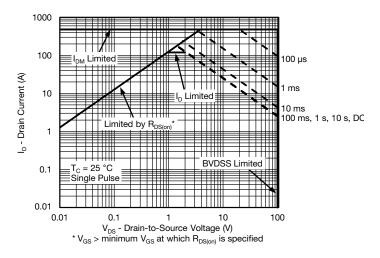


Drain Source Breakdown vs. Junction Temperature

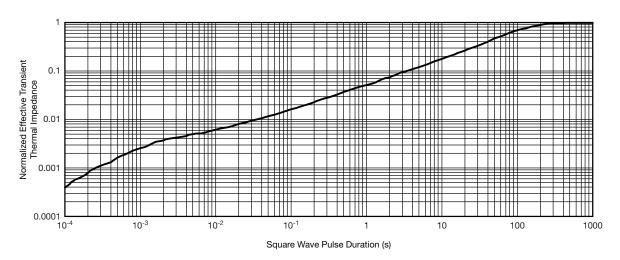


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THERMAL RATINGS ($T_A = 25$ °C, unless otherwise noted)



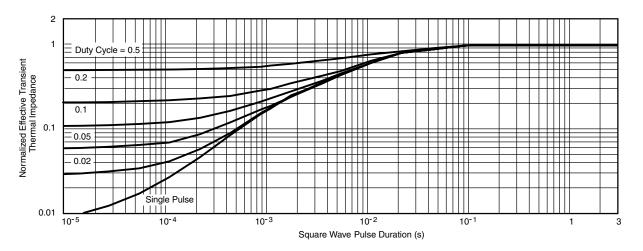
Safe Operating Area



Normalized Thermal Transient Impedance, Junction-to-Ambient



THERMAL RATINGS (T_A = 25 °C, unless otherwise noted)



Normalized Thermal Transient Impedance, Junction-to-Case

Note

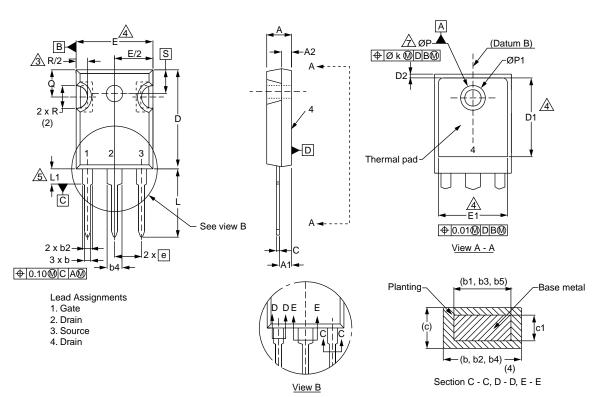
- The characteristics shown in the two graphs
 - Normalized Transient Thermal Impedance Junction to Ambient (25 °C)

can widely vary depending on actual application parameters and operating conditions.

- Normalized Transient Thermal Impedance Junction to Case (25 °C) are given for general guidelines only to enable the user to get a "ball park" indication of part capabilities. The data are extracted from single pulse transient thermal impedance characteristics which are developed from empirical measurements. The latter is valid for the part mounted on printed circuit board - FR4, size 1" x 1" x 0.062", double sided with 2 oz. copper, 100 % on both sides. The part capabilities



TO-247AC



	MILLIM	IETERS	INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
Α	4.58	5.31	0.180	0.209
A1	2.21	2.59	0.087	0.102
A2	1.17	2.49	0.046	0.098
b	0.99	1.40	0.039	0.055
b1	0.99	1.35	0.039	0.053
b2	1.53	2.39	0.060	0.094
b3	1.65	2.37	0.065	0.093
b4	2.42	3.43	0.095	0.135
b5	2.59	3.38	0.102	0.133
С	0.38	0.86	0.015	0.034
c1	0.38	0.76	0.015	0.030
D	19.71	20.82	0.776	0.820
D1	13.08	_	0.515	-

	MILLIM	IETERS	INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
D2	0.51	1.30	0.020	0.051
Е	15.29	15.87	0.602	0.625
E1	13.72	-	0.540	ı
е	5.46	BSC	0.215	BSC
Øk	0.2	254	0.010	
L	14.20	16.25	0.559	0.640
L1	3.71	4.29	0.146	0.169
N	7.62	BSC	0.300	BSC
ØΡ	3.51	3.66	0.138	0.144
Ø P1	-	7.39	ı	0.291
Q	5.31	5.69	0.209	0.224
R	4.52	5.49	0.178	0.216
S	5.51	BSC	0.217	BSC



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